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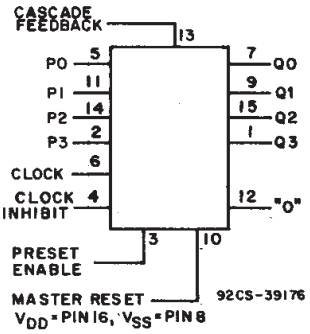
TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor
SCHS079

NOT RECOMMENDED FOR NEW DESIGNS

CD4522B Types

Advance Information/ Preliminary Data



FUNCTIONAL DIAGRAM

CMOS Programmable BCD Divide-by-"N" Counter

High-Voltage Types (20-Volt Rating)

Features:

- *Internally synchronous for high internal and external speeds.*
- *Logic edge-clocked design — increments on positive Clock transition or on negative Clock Inhibit transition.*
- *100% tested for quiescent current at 20-V.*
- *5-V, 10-V, and 15-V parametric ratings.*
- *Standard symmetrical output characteristics.*
- *Maximum input current of 1 μA at 18 V over full package-temperature range: 100 nA at 18 V and 25° C.*
- *Meets all requirements of JEDEC Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices."*

■ CD4522B programmable BCD counter has a decoded "0" state output for divide-by-N applications. In single stage operation the "0" output is tied to the Preset Enable input. The Cascade Feedback allows multiple stage divide-by-N operation without the need for external gating. A HIGH on the Clock Inhibit disables the pulse-counting function. A HIGH on the Master Reset asynchronously resets the divide-by-N operation. The output is presented in BCD format.

The CD4522B types are supplied in 16-lead dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

Applications:

- *Frequency synthesizers*
- *Phase-locked loops*
- *Programmable down counters*
- *Programmable frequency dividers*

3

COMMERCIAL CMOS HIGH VOLTAGE ICs

MAXIMUM RATINGS, *Absolute-Maximum Values:*

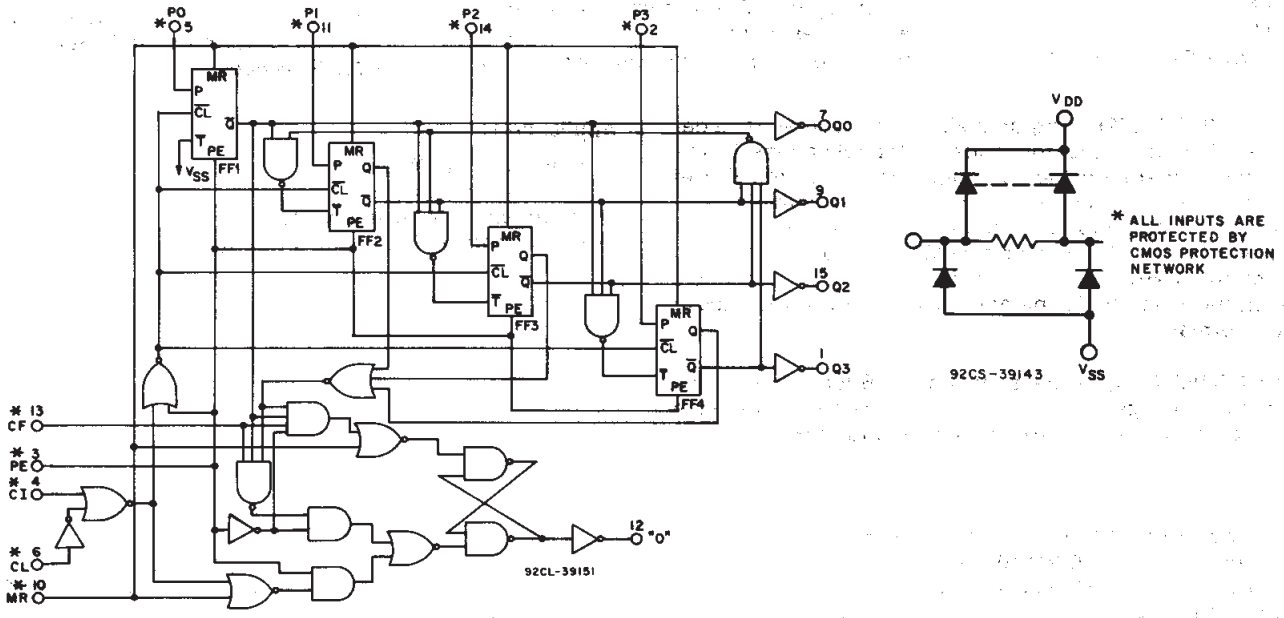
DC SUPPLY-VOLTAGE RANGE, (V_{DD})
(Voltages referenced to V_{SS} Terminal) ..... -0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS ..... -0.5V to V_{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT ..... ±10mA
POWER DISSIPATION PER PACKAGE (P_D):
For T_A = -55°C to +100°C 500mW
For T_A = +100°C to +125°C ..... Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) 100mW
OPERATING-TEMPERATURE RANGE (T_A) ..... -55°C to +125°C
STORAGE TEMPERATURE RANGE (T_{stg}) ..... -65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max ..... +265°C

TRUTH TABLES

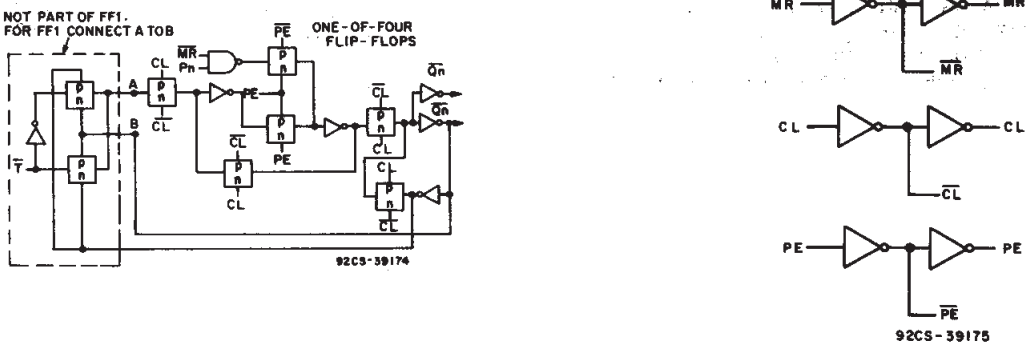
CLOCK	CLOCK INHIBIT	PRESET ENABLE	MASTER RESET	ACTION
0	0	0	0	No Count
⌒	0	0	0	Count Down
X	1	0	0	No Count
1	⌒	0	0	Count Down
X	X	1	0	Preset
X	X	X	1	Reset

X = Don't Care

Count	OUTPUTS			
	Q_0	Q_1	Q_2	Q_3
0	0	0	0	0
1	1	0	0	0
2	0	1	0	0
3	1	1	0	0
4	0	0	1	0
5	1	0	1	0
6	0	1	1	0
7	1	1	1	0
8	0	0	0	1
9	1	0	0	1



a. Basic diagram.



b. Flip-flop detail.

Fig. 1 - Logic diagram for the CD4522B.

RECOMMENDED OPERATING CONDITIONS at T_A = 25°C, except as noted.

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTICS	V_{DD} (V)	LIMITS		UNITS
		Min.	Max.	
Supply-Voltage Range (For T_A = Full Package-Temperature Range		3	18	V
Pulse Width:				
Clock, $tw_{(CC)}$	5	250	—	ns
	10	100	—	
	15	80	—	
Preset Enable, $tw_{(CC)}$	5	250	—	ns
	10	100	—	
	15	80	—	
Master Reset, $tw_{(MR)}$	5	350	—	ns
	10	250	—	
	15	200	—	
Clock Frequency, f_{CL}	5	—	1.5	MHz
	10	—	3.0	
	15	—	4.0	
Clock Rise and Fall Time t_{rCL}, t_{fCL}	5	—	15	μs
	10	—	15	
	15	—	15	
Preset Enable Set-up Time, t_{su}	5	0	—	ns
	10	0	—	
	15	0	—	
Preset Enable Hold Time, t_h	5	75	—	ns
	10	25	—	
	15	20	—	
Master Reset Removal Time, t_{rem}	5	130	—	ns
	10	50	—	
	15	30	—	

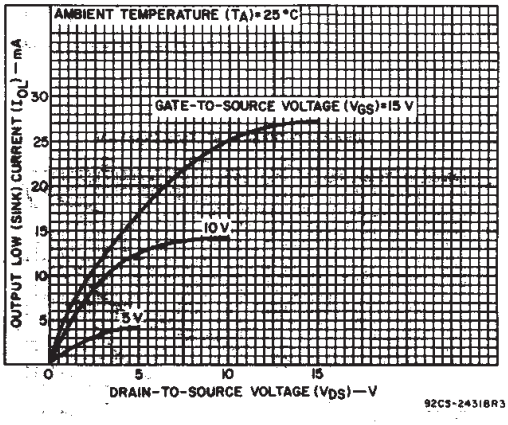


Fig. 2 — Typical output low (sink) current characteristics.

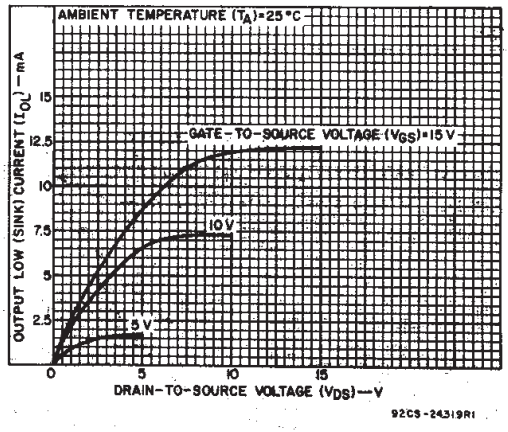


Fig. 3 — Minimum output low (sink) current characteristics.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
								+25			
	V_O (V)	V_{IN} (V)	V_{DD} (V)	-55	-40	+85	+125	Min.	Typ.	Max.	
Quiescent Device Current, I_{DD} Max.	—	0, 5	5	5	5	150	150	—	0.04	5	μA
	—	0, 10	10	10	10	300	300	—	0.04	10	
	—	0, 15	15	20	20	600	600	—	0.04	20	
	—	0, 20	20	100	100	3000	3000	—	0.08	100	
Output Low (Sink) Current I_{OL} Min.	0.4	0, 5	5	0.64	0.61	0.42	0.36	0.51	1	—	mA
	0.5	0, 10	10	1.6	1.5	1.1	0.9	1.3	2.6	—	
	1.5	0, 15	15	4.2	4	2.8	2.4	3.4	6.8	—	
Output High (Source) Current, I_{OH} Min.	4.6	0, 5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	—	
	2.5	0, 5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	—	
	9.5	0, 10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	—	
	13.5	0, 15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	—	
Output Voltage: Low-Level, V_{OL} Max.	—	0, 5	5	0.05				—	0	0.05	V
	—	0, 10	10	0.05				—	0	0.05	
	—	0, 15	15	0.05				—	0	0.05	
Output Voltage: High-Level V_{OH} Min.	—	0, 5	5	4.95				4.95	5	—	
	—	0, 10	10	9.95				9.95	10	—	
	—	0, 15	15	14.95				14.95	15	—	
Input low Voltage, V_{IL} Max.	0.5, 4.5	—	5	1.5				—	—	1.5	
	1, 9	—	10	3				—	—	3	
	1.5, 13.5	—	15	4				—	—	4	
Input High Voltage, V_{IH} Min.	0.5, 4.5	—	5	3.5				3.5	—	—	
	1, 9	—	10	7				7	—	—	
	1.5, 13.5	—	15	11				11	—	—	
Input Current, I_{IN} Max.	—	0, 18	18	±0.1	±0.1	±1	±1	—	$\pm 10^{-5}$	±0.1	μA

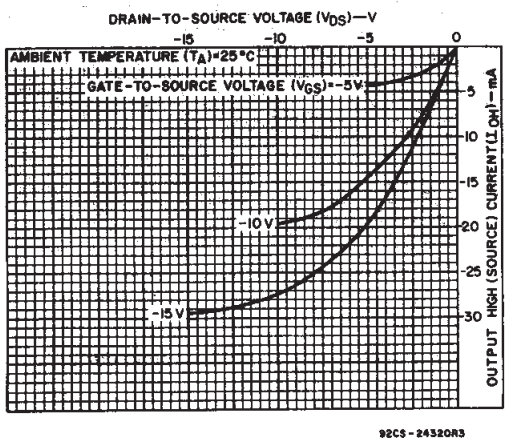


Fig. 4 — Typical output high (source) current characteristics.

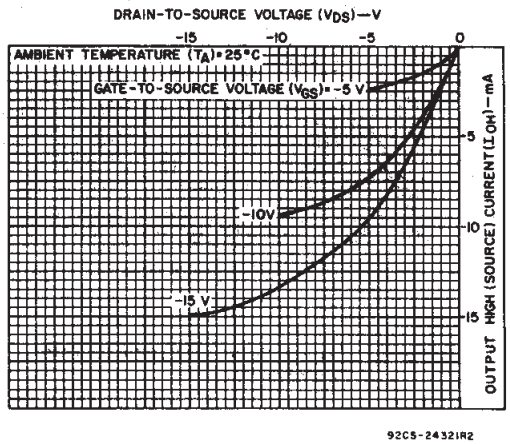


Fig. 5 — Minimum output high (source) current characteristics.

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25°C$, Input t_r, $t_f = 20$ ns, $C_l = 50$ pF, R_L, = 200 kΩ

CHARACTERISTIC	TEST CONDITIONS	LIMITS			UNITS
	V_{DD} (V)	Min.	Typ.	Max.	
Propagation Delay Time; t_{PHL}, t_{PLH}: Clock to "Q" outputs	5	—	550	1100	ns
	10	—	225	450	
	15	—	160	320	
Clock to "0" output	5	—	420	710	ns
	10	—	160	270	
	15	—	110	190	
Clock inhibit to "Q" outputs	5	—	270	540	ns
	10	—	100	200	
	15	—	70	140	
Master reset to "Q" outputs	5	—	270	540	ns
	10	—	100	200	
	15	—	70	140	
Preset Enable Setup Time, t_{su}	5	—	0	0	ns
	10	—	0	0	
	15	—	0	0	
Preset Enable Hold Time, t_h	5	—	75	150	ns
	10	—	25	50	
	15	—	20	40	
Master Reset Removal Time, t_{rem}	5	—	130	260	ns
	10	—	50	100	
	15	—	30	60	
Transition Time, t_{THL}, t_{TLH}	5	—	100	200	ns
	10	—	50	100	
	15	—	40	80	
Minimum Pulse Width Clock, $t_{W(CL)}$	5	—	125	250	ns
	10	—	50	100	
	15	—	40	80	
Preset Enable, $t_{W(PE)}$	5	—	125	250	ns
	10	—	50	100	
	15	—	40	80	
Master Reset, $t_{W(MR)}$	5	—	175	350	ns
	10	—	125	250	
	15	—	100	200	
Max Clock Freq, f_{CL}	5	—	3	1.5	MHz
	10	—	6	3.0	
	15	—	8	4.0	
Max Clock or Clock Inhibit Rise & Fall Time, t_{TLH}, t_{THL}	5	—	—	15	us
	10	—	—	15	
	15	—	—	15	
Input Capacitance, C_{IN}	Any Input	—	5	7.5	pF

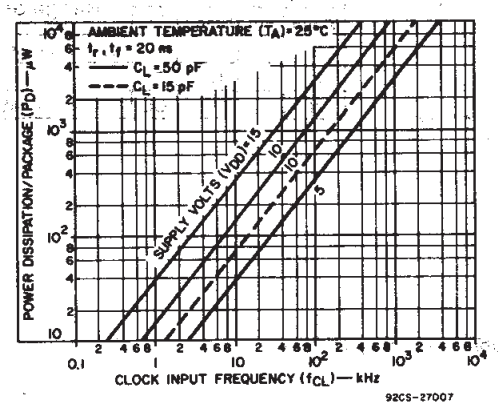
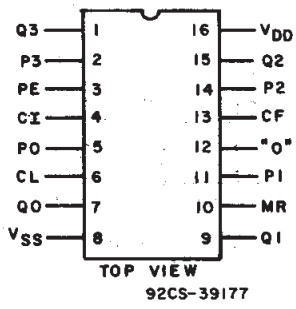


Fig. 6 — Typical dynamic power dissipation vs. frequency.



TERMINAL ASSIGNMENT

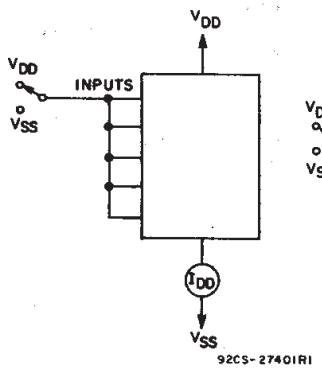


Fig. 7 — Quiescent device current test circuit.

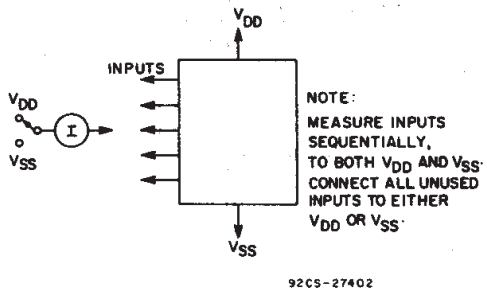


Fig. 8 — Input current test circuit.

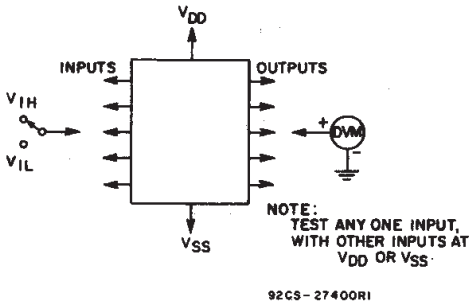
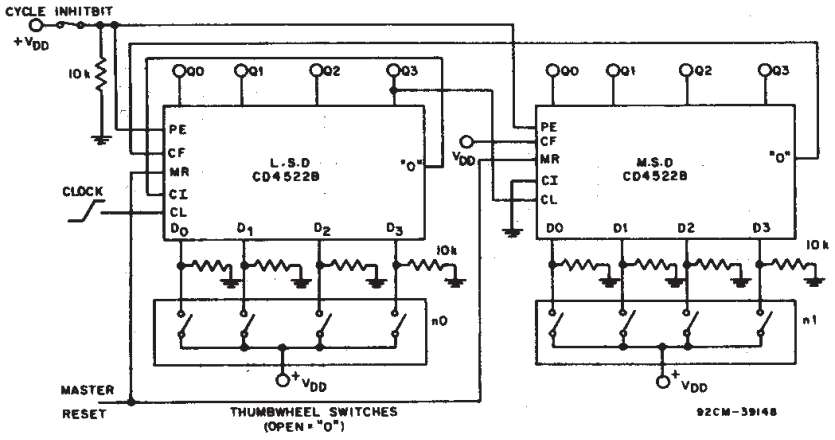


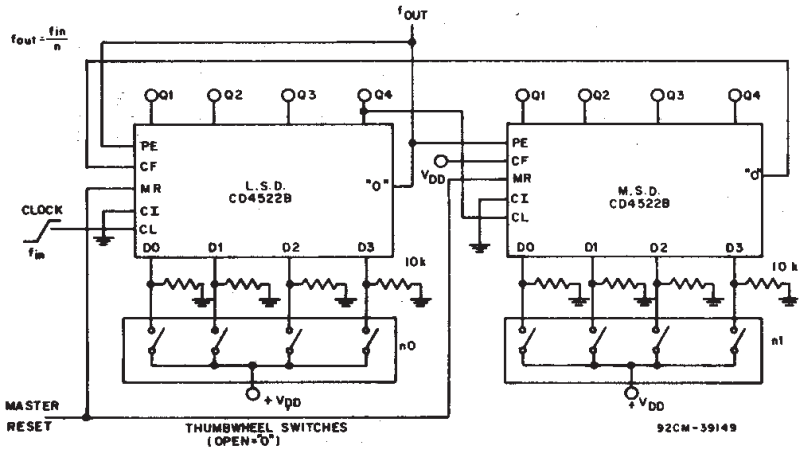
Fig. 9 — Input voltage test circuit.

APPLICATION CIRCUITS



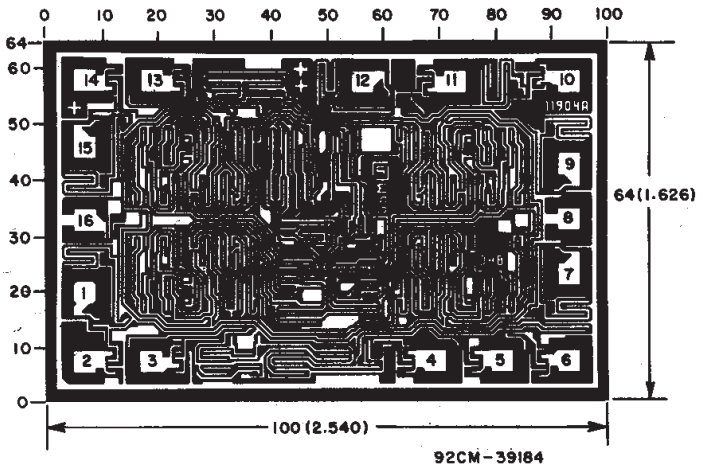
From		To		Range of N
Stage	Pin	Stage	Pin	
LSD	"0"	All	PE	LSD < N < MSD
N	"0"	N-1	CF	LSD + 1 < N < MSD
N	"0_3"	N+1	CL	LSD < N < MSD-1

Fig. 10 — 2-Stage Programmable Down Counter (One Cycle)



From		To		Range of N
Stage	Pin	Stage	Pin	
LSD	"0"	All	PE	LSD < N < MSD
N	"0"	N-1	CF	LSD + 1 < N < MSD
N	"0_3"	N+1	CL	LSD < N < MSD-1

Fig. 11 — 2-Stage Programmable Frequency Divider



Dimensions and pad layout for CD4522BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

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